

<b>Notice of References Cited</b>	Application/Control No. 10/532,084		Applicant(s)/Patent Under Reexamination YASUMURA ET AL.	
	Examiner Ives Wu		Art Unit 1724	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0055030 A1	05-2002	Okumura et al.	429/34
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 61-009424	01-1986	Japan	Hideo et al	C08F 299/06
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	R					
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**NON-PATENT DOCUMENTS**

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